

## AO4419



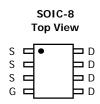
# P-Channel Enhancement Mode Field Effect Transistor

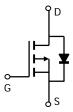
# **General Description**

The AO4419 uses advanced trench technology to provide excellent  $R_{DS(ON)}$ , and low gate charge. This device is suitable for use as a load switch or in PWM applications. Standard Product AO4419 is Pb-free (meets ROHS & Sony 259 specifications). AO4419L is a Green Product ordering option. AO4419 and AO4419L are electrically identical.

## **Features**

$$\begin{split} &V_{DS} \left( V \right) = \text{-}30V \\ &I_{D} = \text{-}9.7 \text{ A } \left( V_{GS} = \text{-}10V \right) \\ &R_{DS(ON)} < 20 \text{m}\Omega \left( V_{GS} = \text{-}10V \right) \\ &R_{DS(ON)} < 35 \text{m}\Omega \left( V_{GS} = \text{-}4.5V \right) \end{split}$$





Absolute Maximum Ratings T <sub>A</sub> =25°C unless otherwise noted								
Parameter		Symbol	Maximum	Units				
Drain-Source Voltage		$V_{DS}$	-30	V				
Gate-Source Voltage		$V_{GS}$	±20	V				
Continuous Drain	T <sub>A</sub> =25°C		-9.7					
Current <sup>A</sup>	T <sub>A</sub> =70°C	$I_D$	-8.1	Α				
Pulsed Drain Current <sup>B</sup>		I <sub>DM</sub>	-40					
	T <sub>A</sub> =25°C	D	3	W				
Power Dissipation A	T <sub>A</sub> =70°C	$-P_D$	2.1	VV				
Junction and Storage Temperature Range		$T_J$ , $T_{STG}$	-55 to 150	°C				

Thermal Characteristics								
Parameter	Symbol	Тур	Max	Units				
Maximum Junction-to-Ambient A	t ≤ 10s	Ь	31	40	°C/W			
Maximum Junction-to-Ambient <sup>A</sup>	Steady-State	Steady-State R <sub>θJA</sub>		75	°C/W			
Maximum Junction-to-Lead <sup>C</sup>	Steady-State	$R_{ heta JL}$	21	30	°C/W			

## Electrical Characteristics (T<sub>J</sub>=25°C unless otherwise noted)

Symbol	Parameter	Parameter Conditions		Тур	Max	Units				
STATIC PARAMETERS										
$BV_{DSS}$	Drain-Source Breakdown Voltage	$I_D = -250 \mu A, V_{GS} = 0 V$	-30			V				
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> =-24V, V <sub>GS</sub> =0V			-1	μА				
-033		Т <sub>J</sub> =55°С			-5	μιν				
$I_{GSS}$	Gate-Body leakage current	V <sub>DS</sub> =0V, V <sub>GS</sub> =±20V			±100	nA				
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS} I_{D}=-250\mu A$	-1.4	-2	-2.7	V				
$I_{D(ON)}$	On state drain current	V <sub>GS</sub> =-10V, V <sub>DS</sub> =-5V	-40			Α				
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> =-10V, I <sub>D</sub> =-9.7A		16	20	mΩ				
		T <sub>J</sub> =125°C		20.9	26	11122				
		$V_{GS}$ =-4.5V, $I_D$ =-7A		26	35	mΩ				
g <sub>FS</sub>	Forward Transconductance	$V_{DS}$ =-5V, $I_{D}$ =-9.7A		21.7		S				
$V_{SD}$	Diode Forward Voltage	I <sub>S</sub> =-1A,V <sub>GS</sub> =0V		-0.7	-1	V				
$I_S$	Maximum Body-Diode Continuous Curr			-1.2	Α					
DYNAMIC	PARAMETERS									
C <sub>iss</sub>	Input Capacitance			1573	1900	pF				
Coss	Output Capacitance	$V_{GS}$ =0V, $V_{DS}$ =-15V, f=1MHz		319		pF				
C <sub>rss</sub>	Reverse Transfer Capacitance			211		pF				
$R_g$	Gate resistance	$V_{GS}$ =0V, $V_{DS}$ =0V, f=1MHz		6.7	8	Ω				
SWITCHI	NG PARAMETERS									
Q <sub>g</sub> (10V)	Total Gate Charge (10V)			26.4	32	nC				
Q <sub>g</sub> (4.5V)	Total Gate Charge (4.5V)	Gate Charge (4.5V) V <sub>GS</sub> =-10V, V <sub>DS</sub> =-15V, I <sub>D</sub> =-9.7A		13.7	17	nC				
$Q_{gs}$	Gate Source Charge	VGS10V, VDS10V, ID0.17A		3.8		nC				
$Q_{gd}$	Gate Drain Charge			6.8		nC				
$t_{D(on)}$	Turn-On DelayTime			9.5		ns				
t <sub>r</sub>	Turn-On Rise Time	$V_{GS}$ =-10V, $V_{DS}$ =-15V, $R_L$ =1.5 $\Omega$ ,		8		ns				
$t_{D(off)}$	Turn-Off DelayTime	$R_{GEN}$ =3 $\Omega$		44.2		ns				
t <sub>f</sub>	Turn-Off Fall Time	]		22.2		ns				
t <sub>rr</sub>	Body Diode Reverse Recovery Time	I <sub>F</sub> =-9.7A, dI/dt=100A/μs		25.2	31	ns				
Q <sub>rr</sub>	Body Diode Reverse Recovery Charge	I <sub>F</sub> =-9.7A, dI/dt=100A/μs		14.1		nC				

A: The value of R  $_{\theta JA}$  is measured with the device mounted on 1 in  $^2$  FR-4 board with 2 oz. Copper, in a still air environment with T  $_A$  =25 °C.

Rev 2 : May 2005

THIS PRODUCT HAS BEEN DESIGNED AND QUALIFIED FOR THE CONSUMER MARKET. APPLICATIONS OR USES AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS ARE NOT AUTHORIZED. AOS DOES NOT ASSUME ANY LIABILITY ARISING OUT OF SUCH APPLICATIONS OR USES OF ITS PRODUCTS. AOS RESERVES THE RIGHT TO IMPROVE PRODUCT DESIGN, FUNCTIONS AND RELIABILITY WITHOUT NOTICE.

The value in any given application depends on the user's specific board design. The current rating is based on the t ≤ 10s thermal resistance rating.

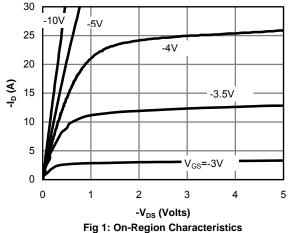
B: Repetitive rating, pulse width limited by junction temperature.

C. The R  $_{\theta JA}$  is the sum of the thermal impedence from junction to lead R  $_{\theta JL}$  and lead to ambient.

D. The static characteristics in Figures 1 to 6,12,14 are obtained using 80 µs pulses, duty cycle 0.5% max.

E. These tests are performed with the device mounted on 1 in  $^2$  FR-4 board with 2oz. Copper, in a still air environment with T  $_A$ =25°C. The SOA curve provides a single pulse rating.

### TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS



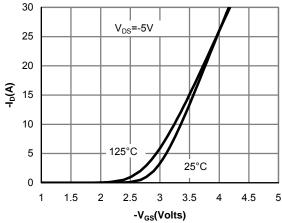


Figure 2: Transfer Characteristics

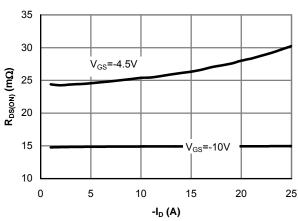


Figure 3: On-Resistance vs. Drain Current and **Gate Voltage** 

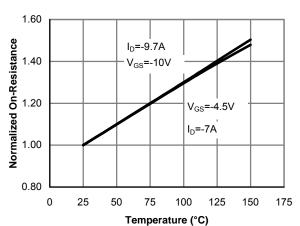


Figure 4: On-Resistance vs. Junction Temperature

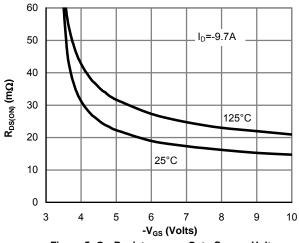


Figure 5: On-Resistance vs. Gate-Source Voltage

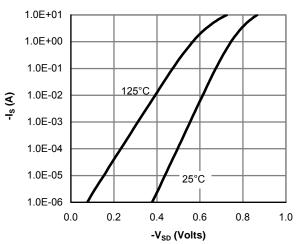


Figure 6: Body-Diode Characteristics

### TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

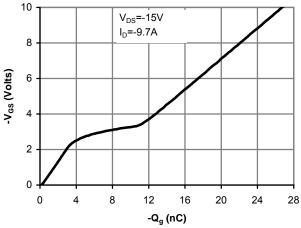


Figure 7: Gate-Charge Characteristics

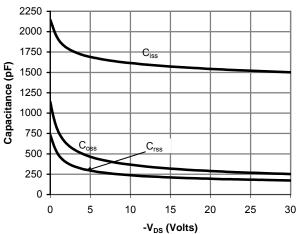


Figure 8: Capacitance Characteristics

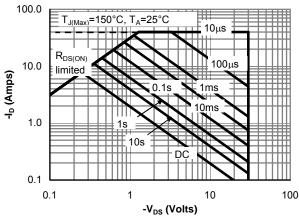


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

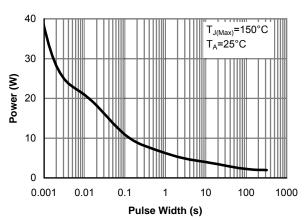


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

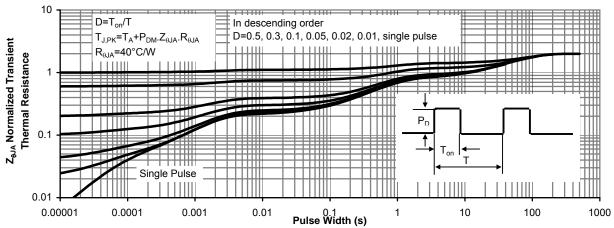


Figure 11: Normalized Maximum Transient Thermal Impedance